# OMR117AHVSR OMR117AHVST OMR117AHVNM OMR117AHVNH 100 kRAD RADIATION TOLERANT 1.5 AMP POSITIVE ADJUSTABLE VOLTAGE REGULATOR



100K Rad Tolerant Three Terminal, Precision Adjustable Positive Voltage Regulator In Hermetic Packages

## **FEATURES**

- Electrically Similar To Industry Standard LM117AHV
- Adjustable Output Voltage
- Built In Thermal Overload Protection
- Short Circuit Current Limiting
- Available In Four Hermetic Package Styles
- Maximum Output Voltage Tolerance Is Guaranteed to ± 1%
- Radiation Tolerant up to 150 K Rad (Si)
- Available Hi-Rel Screened, Class B and Class S, MIL-STD-883

# DESCRIPTION

These three terminal positive regulators are supplied in high density hermetically sealed packages and available Hi-Rel screened. All protective features are designed into the circuit, including thermal shutdown, current-limiting, and safe-area control. With heat sinking, these devices can deliver up to 1.5 amps of output current. These units also feature output voltages that can be fixed from 1.2 volts to 57 volts using external resistors. These devices are ideally suited for Space applications where small size, high reliability, and radiation tolerance is required. The high level of Radiation Tolerance of these devices makes them a desirable choice for LEO and many MEO and GEO communication satellites. Radiation testing is performed on a single wafer by wafer basis. Random die samples per wafer are selected, packaged and radiation tested to qualify each individual semiconductor wafer-by-wafer.

# ABSOLUTE MAXIMUM RATINGS T<sub>c</sub> @ 25°C

Power Dissipation: TO-205
TO-257/SMD/ D <sup>2</sup> Pac
Input - Output Voltage Differential 60 V
Operating Junction Temperature Range 55°C to + 150°C
Storage Temperature Range 65°C to + 150°C
Lead Temperature (Soldering 10 seconds) 300°C
Thermal Resistance, Junction to Case:
TO-205
TO-257(Isolated), D <sup>2</sup> Pac (Isolated) 4.2°C/W
TO-257 (Non-Isolated) and SMD-1 3.5°C/W
Maximum Output Current: TO-2055 A
Case-All Others 1.5A
Recommended Operating Conditions:
Output Voltage Range
Input Voltage Range 4.25 to 61.25 VDC
Radiation Tolerant - Total Dose 100 K Rad (Si)
Surface Mount Package Soldering Temperature

0 04 R2 Supersedes 9 12 R1

# Omnirel

## 

Parameter	Symbol	Test Conditions	Min.	Max.	Unit	
Reference Voltage	V <sub>REF</sub>	$V_{DIFF} = 3.0V, T_A = 25^{\circ}C$		1.238	1.262	
(Note 4)		$V_{DIFF} = 3.3V$	•	1.225	1.270	v v
		$V_{DIFF} = 40V$	•	1.225	1.270	
		$V_{DIFF} = 60V$	•	1.225	1.270	
Line Regulation	R <sub>LINE</sub>	$3.0V \leq V_{\text{DIFF}} \leq 40V, V_{\text{out}} = V_{\text{ref}}, T_{\text{A}} = 25^{\circ}\text{C}$			4.5	
(Note 1, 4)		$3.3V \leq V_{DIFF} \leq 40V,  V_{out} = V_{ref}$	•		9	mV
		$40V \le V_{DIFF} \le 60V$ , $V_{out} = V_{ref}$ , $T_A = 25^{\circ}C$			5	
		$40V \le V_{DIFF} \le 60V$ , $V_{out} = V_{ref}$	•		10	
Load Regulation	R <sub>LOAD</sub>	$V_{DIFF} = 3.0V$ , $10mA \le I_L \le 1.5A$ , $T_A = 25^{\circ}C$			15	
(Note 1, 4)		$V_{DIFF}$ = 3.3V, 10mA $\leq I_L \leq$ 1.5A	•		15	mV
		$V_{DIFF}$ = 40V, 10mA $\leq$ I <sub>L</sub> $\leq$ 300mA, T <sub>A</sub> = 25°C			15	
		$V_{DIFF}$ = 40V, 10mA $\leq I_{L} \leq$ 195mA	•		15	
		$V_{DIFF}$ = 60V, 10mA $\leq$ I <sub>L</sub> $\leq$ 30mA	•		15	
Thermal Regulation	V <sub>RTH</sub>	V <sub>in</sub> = 14.6V, I <sub>L</sub> = 1.5A			5	mV
		$P_d$ = 20 Watts, t = 20 ms, $T_A$ = 25°C				
Ripple Rejection	R <sub>N</sub>	f = 120 Hz, V <sub>out</sub> = V <sub>ref</sub>	•	66		dB
		$C_{Adj} = 10 \ \mu\text{F}, \ I_{out} = 100 \ \text{mA}$				
Adjustment Pin	I <sub>Adj</sub>	$V_{DIFF} = 3.0V, T_A = 25^{\circ}C$			100	
Current		$V_{DIFF} = 3.3V$	•		100	μA
		$V_{DIFF} = 40V$	•		100	
(Note 4)		$V_{DIFF} = 60V$	•		100	
Adjustment Pin	$\Delta I_{Adj}$	$V_{DIFF} = 3.0V$ , $10mA \le I_L \le 1.5A$ , $T_A = 25^{\circ}C$			5	
Current Change		$V_{DIFF}$ = 3.3V, 10mA $\leq I_L \leq$ 1.5A	•		5	
		$V_{DIFF}$ = 40V, 10mA $\leq I_L \leq$ 300mA, $T_A$ = 25°C			5	
		$V_{DIFF}$ = 40V, 10mA $\leq I_{L} \leq$ 195mA	•		5	μA
		$3.0V \le V_{DIFF} \le 40V, T_A = 25^{\circ}C$			5	
		$3.3V \le V_{DIFF} \le 40V$	•		5	
		$3.3V \le V_{DIFF} \le 60V$	•		5	
Minimum Load Current	ILmin	$V_{DIFF} = 3.0V, V_{out} = 1.4V$ (forced)			10	
		$V_{DIFF} = 3.3V$ , $V_{out} = 1.4V$ (forced)	•			mA
		$V_{DIFF} = 40V, V_{out} = 1.4V$ (forced)	•			
		$V_{DIFF} = 60V, V_{out} = 1.4V$ (forced)	•			
Current Limit	I <sub>CL</sub>	V <sub>DIFF</sub> = 5V	•	1.5	3.5	
(Note 2, 4)		$V_{DIFF} = 40V, T_A = 25^{\circ}C$		0.3	1.5	A
		$V_{DIFF} = 60V, T_A = 25^{\circ}C$		0.05	0.5	

1. Load and Line Regulation are measured at a constant junction temperature using a low duty cycle pulse technique.

Changes in output voltage due to heating effects must be taken into account separately.

2.If not tested, shall be guaranteed to the specified limits.3.The • denotes the specifications which apply over the full temperature range.

4.Refer to curves for typical characteristics versus Total Dose Radiation Levels.

# **RADIATION TEST PROGRAM**

The following chart is a summary of the test data collected on Radiation Tolerant OMR117AHV at various doses. The chart depicts the Total Radiation Dose that each device was exposed to on a step stress irradiation basis prior to failure. Failure is defined as any electrical test that does not meet the limits of the device per the published data sheet specifications after radiation testing.

Omnirel P/N	5K	10K	20K	30K	50K	60K	70K	80K	100K	150K	200K RAD
OMR117AHV											
Test Points				Χ	Х				Х	Х	



#### OMR117AHVSR, OMR117AHVST, OMR117AHVNM, OMR117AHVNH

## **OMNIREL'S RADIATION TEST PROCEDURE**

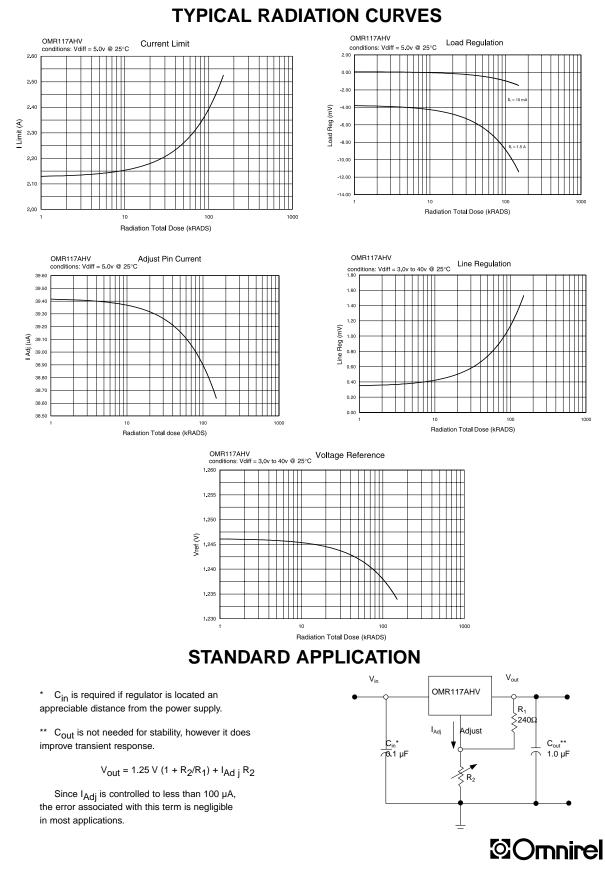
- Radiation Testing is performed on a single wafer by wafer basis.
- Each wafer is identified and a random sample of 5 die per wafer is selected.
- The die are then individually assembled in a hermetic package, data logged, electrically tested, hi-rel screened and then submitted to radiation testing.
- The packaged die are submitted to Steady State Total Dose radiation per Method 1019, Condition A, at a dose rate of 50 RAD/sec biased at maximum supply voltage.
- Final electrical test is performed within two hours of both Total Dose Radiation level from a Cobalt 60 source and 168 hr, 100°C annealing process. Read and record data including two non-radiated control samples.
- The wafer is then qualified only if samples from wafers meet full electrical specifications after 150% of total dose rating as specified in each product data sheet.
- Omnirel's controlling specifications are as follows: For Voltage Regulators the controlling specification is MIL-PRF- 38534/MIL-STD-883. For Rectifiers/Schottky the controlling specification is MIL-PRF-19500/MIL-STD-750.

Standard Class Level Screening Per MIL-PRF-38535							
Screen	*Lev	/el B	*Level S				
	Test Method	Required	Test Method	Required			
Wafer Lot Acceptance			5007	100%			
Non-destructive Bond Pull							
Pre-Cap Visual Inspection	2010	100%	2010	100%			
Temperature Cycle	1010	100%	1010	100%			
Constant Acceleration	2001	100%	2001	100%			
Visual Inspection		100%		100%			
PIND Test			2020	100%			
Serialization				100%			
Pre-Burn-In Electrical	Data Sheet	100%	Data Sheet	100%			
Burn-In	1015/160 hrs.	100%	1015/240hrs.	100%			
Interim Electrical			Data Sheet	100%			
PDA Calculations	5% Functional	Lot	5% Functional	Lot			
Final Electrical	Data Sheet	100%	Data Sheet	100%			
Fine & Gross Seal	1014	100%	1014	100%			
Radiographic			2012/Two Views	100%			
Conformance Inspection	GR A&B	Sample	GR A&B	Sample			
Final Visual Inspection	2009	Sample	2009	Sample			

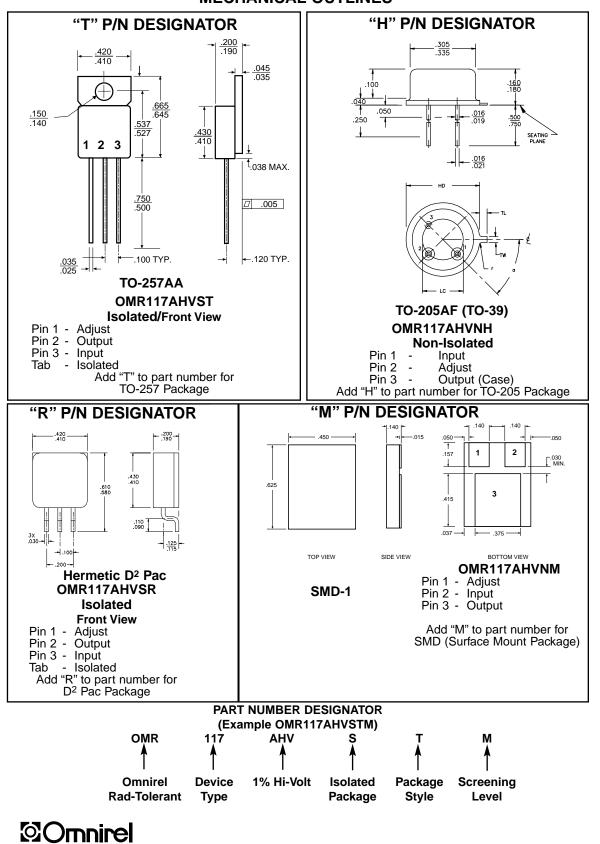
# AVAILABLE PRODUCT SCREENING

\*Note: For "B" Level Screening add "M" to part number, for "S" Level Screening add "S" to part number. See Part Number Designator.

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OMR117AHVSR, OMR117AHVST, OMR117AHVNM, OMR117AHVNH



### OMR117AHVSR, OMR117AHVST, OMR117AHVNM, OMR117AHVNH MECHANICAL OUTLINES

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# THANK YOU FOR YOUR INTEREST IN OMNIREL'S PRODUCTS!

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